ABSTRACT:

A method for testing an integrated circuitry and an integrated circuit having a plurality of functional components and having junction/switch test components in interconnecting channels between functional components.

The invention proposes a testing method and associated arrangement for electronic circuitry that combines functional components that are interconnected by handshake channels. Various of such channels are now provided with an inbreaking junction and an outbreaking switch as a test component pair. The junction has two passive ports and one active port. The switch has one passive port and two active ports that are selected through a passive control port. In this way inbreaking into an outbreaking from the channel is rendered feasible. Now inbreaking is done on a first channel, and outbreaking on a second channel, so that thereby all components are tested that lie between the first channel's junction and the second channel's switch.

This Sheet Has Been Replaced

